INTEGRATED CIRCUITS

DATA SHEET

74F139Dual 1-of-4 decoder/demultiplexer

Product specification

1990 Feb 23

IC15 Data Handbook





74F139

FEATURES

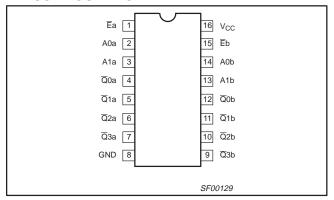
- Demultiplexing capability
- Two independent 1-of-4 decoders
- Multifunction capability

DESCRIPTION

The 74F139 is a high speed, dual 1-of-4 decoder/demultiplexer. This device has two independent decoders, each accepting two binary weighted inputs (A0n, A1n) and providing four mutually exclusive active-Low outputs ($\overline{Q}0n-\overline{Q}3n$). Each decoder has an active-Low Enable (\overline{E}). When \overline{E} is High, every output is forced High. The Enable can be used as the Data input for a 1-of-4 demultiplexer application.

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F139	5.3ns	13mA

PIN CONFIGURATION



ORDERING INFORMATION

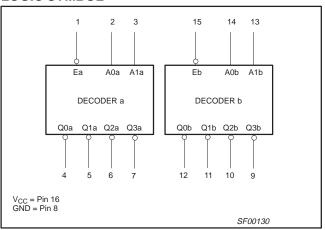
DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V $\pm 10\%$, T_{amb} = 0°C to +70°C	PKG DWG #
16-pin plastic DIP	N74F139N	SOT38-4
16-pin plastic SO	N74F139D	SOT109-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

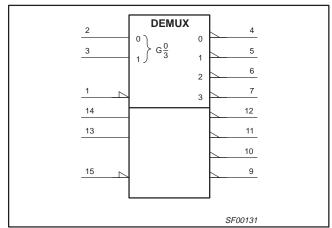
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Ana, Anb	Address inputs	1.0/1.0	20μA/0.6mA
Ēa, Ēb	Enable inputs (active Low)	1.0/1.0	20μA/0.6mA
Q0n−Q3n	Data outputs (active Low)	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20μA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL

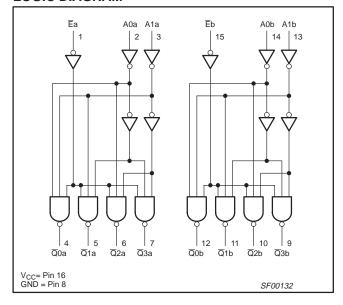


IEC/IEEE SYMBOL



74F139

LOGIC DIAGRAM



FUNCTION TABLE

	INPUTS			OUTPUTS								
Ē	A0	A 1	Q0	Q1	Q 2 Q 3							
Н	Х	Х	Н	Н	Н	Н						
L	L	L	L	Н	Н	Н						
L	Н	L	Н	L	Н	Н						
L	L	Н	Н	Н	L	Н						
L	Н	Н	Н	Н	Н	L						

NOTES:

H = High voltage level
L = Low voltage level
X = Don't care

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	−30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	−0.5 to +V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

CVMDOL	PARAMETER		UNIT		
SYMBOL	PARAMETER	MIN	NOM	MAX	UNII
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _{amb}	Operating free-air temperature range	0		+70	°C

74F139

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

CVMDOL	DADAMETED	TEST CONDITIO	NC1		LIMITS		UNIT
SYMBOL	PARAMETER	TEST CONDITIO	NO.	MIN	TYP ²	MAX	
V	High level output veltage	$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}	2.5			V
V _{OH}	High-level output voltage	$V_{IH} = MIN, I_{OH} = MAX$	±5%V _{CC}	2.7	3.4		V
V	Low level cutout veltage	$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}		0.30	0.50	V
V _{OL}	Low-level output voltage	V _{IH} = MIN, I _{OL} = MAX	±5%V _{CC}		0.30	0.50	V
V _{IK}	Input clamp voltage	$V_{CC} = MIN, I_I = I_{IK}$	$V_{CC} = MIN, I_I = I_{IK}$				V
I _I	Input current at maximum input voltage	$V_{CC} = MAX, V_I = 7.0V$				100	μΑ
I _{IH}	High-level input current	$V_{CC} = MAX, V_I = 2.7V$				20	μА
I _{ILL}	Low-level input current	$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA
I _{OS}	Short-circuit output current ³	$V_{CC} = MAX$	-60		-150	mA	
Icc	Supply current (total)	$V_{CC} = MAX$			13	20	mA

NOTES:

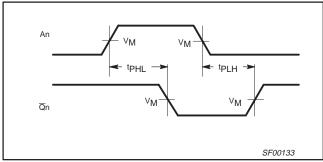
- 1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
 Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, IOS tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

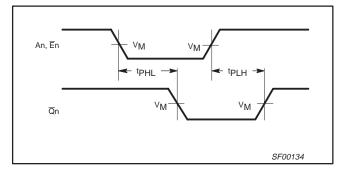
SYMBOL	PARAMETER	TEST CONDITION	Ta	CC = +5.0 amb = +25° 50pF, R _L =	C	V _{CC} = +5. T _{amb} = 0°0 C _L = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay A0 ir A1 to Qna, Qnb	Waveform 1, 2	3.5 4.0	5.3 6.1	7.0 8.0	3.0 4.0	8.0 9.0	ns
t _{PLH} t _{PHL}	Propagation delay En to Qna, Qnb	Waveform 2	3.5 3.0	5.4 4.7	7.0 6.5	3.5 3.0	8.0 7.5	ns

AC WAVEFORMS

For all waveforms, $V_M = 1.5V$



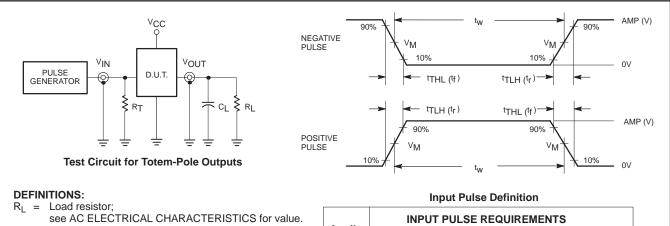
Waveform 1. Propagation Delay for Inverting Outputs



Waveform 2. Propagation Delay for Non-Inverting Outputs

74F139

TEST CIRCUIT AND WAVEFORMS



C_L = Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of

pulse generators.

family	INP	INPUT PULSE REQUIREMENTS											
lallilly	amplitude	V_{M}	rep. rate	t _w	t _{TLH}	t _{THL}							
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns							

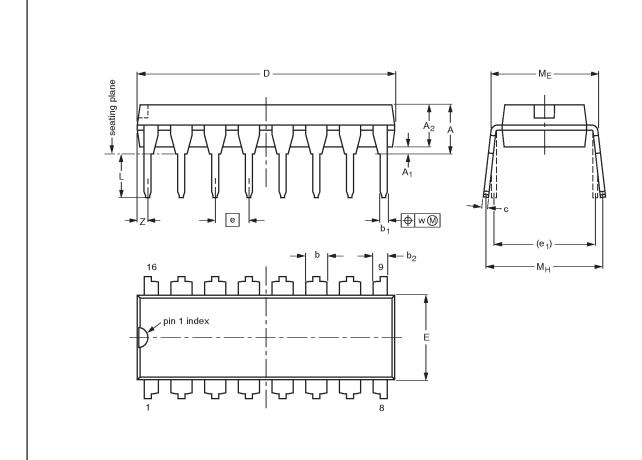
SF00006

Dual 1-of-4 decoder/demultiplexer

74F139

DIP16: plastic dual in-line package; 16 leads (300 mil)

SOT38-4



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	O	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

scale

10 mm

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE	IEC JE	REFER	RENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT38-4				□ •	92-11-17 95-01-14	

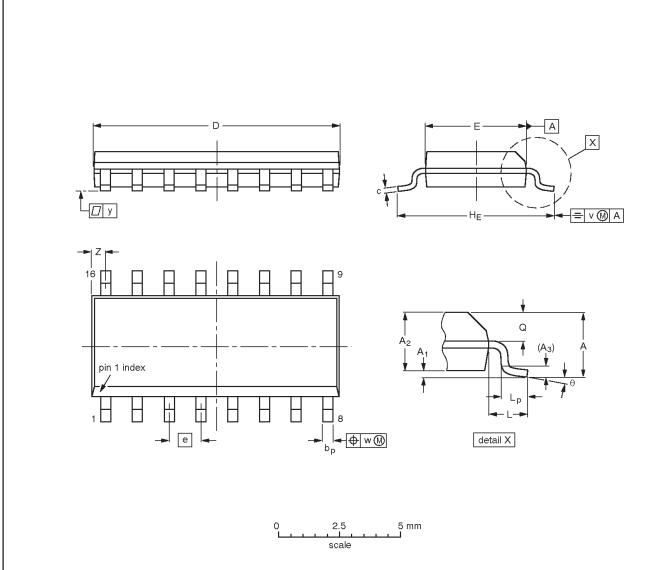
1990 Feb 23 6

Dual 1-of-4 decoder/demultiplexer

74F139

SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	bp	c	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	10.0 9.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.39 0.38	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016		0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT109-1	076E07S	MS-012AC				-95-01-23 97-05-22

1990 Feb 23 7

Dual 1-of-4 decoder/demultiplexer

74F139

Data sheet status

Data sheet status	Product status	Definition [1]	
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.	
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.	
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible produc	

^[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Disclaimers

Life support — These products are not designed for use in life support appliances, devices or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips Semiconductors customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips Semiconductors for any damages resulting from such application.

Right to make changes — Philips Semiconductors reserves the right to make changes, without notice, in the products, including circuits, standard cells, and/or software, described or contained herein in order to improve design and/or performance. Philips Semiconductors assumes no responsibility or liability for the use of any of these products, conveys no license or title under any patent, copyright, or mask work right to these products, and makes no representations or warranties that these products are free from patent, copyright, or mask work right infringement, unless otherwise specified.

Philips Semiconductors 811 East Arques Avenue P.O. Box 3409 Sunnyvale, California 94088–3409 Telephone 800-234-7381 © Copyright Philips Electronics North America Corporation 1998 All rights reserved. Printed in U.S.A.

print code Date of release: 10-98

Document order number: 9397-750-05077

Let's make things better.

Philips Semiconductors



